

**Notice of References Cited**

Application/Control No.

10/585,655

Applicant(s)/Patent Under  
Reexamination  
TAKUMAI ET AL.

Examiner

DEVONA E. FAULK

Art Unit

2615

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**NON-PATENT DOCUMENTS**

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